

650V IGBT4

the optimized device
for large current modules
with 10 μ s short-circuit withstand time

PCIM 2010

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Outline

- Motivation
- Design and technology of the 650V IGBT4
- Static and dynamic characteristics
- Softness
- Short-circuit behavior

Motivation

■ 600V IGBT3

- still a benchmarking device
 - but: optimized for smaller power application and very low stray inductance applications (high dI/dt)
 - overvoltage $V_{CE,max} = L \cdot dI/dt$
- provide additional degrees of freedom for applications with larger currents / larger stray inductance

■ 650V IGBT4

- higher blocking voltage capability
- lower overshoot voltage $V_{CE,max}$
- lower turn-off current slope dI/dt
- enhanced short circuit withstand time

Why 650V blocking voltage capability?

3-level topology:

■ Europe typical: 3x 400 V_{AC}

□ 240V phase-neutral nominal

■ North America: 3x 480V_{AC}

□ 277V phase-neutral nominal

■ UPS: 15% over-voltage capability

■ DC bus voltage: +/- 450V

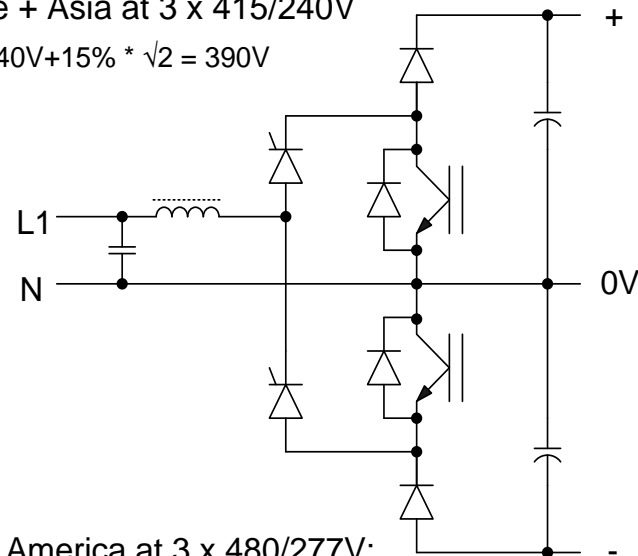
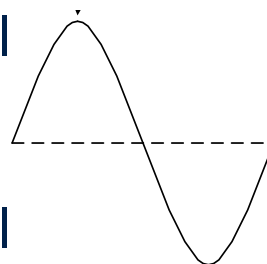
■ load steps in UPS effect DC voltage variations

→ standard 600V IGBT and Diodes

not recommendable for 3-Level UPS

Operation in Europe + Asia at 3 x 415/240V

$$V_{\text{peak(max)}} = 240\text{V} + 15\% \cdot \sqrt{2} = 390\text{V}$$



Operation in North America at 3 x 480/277V:

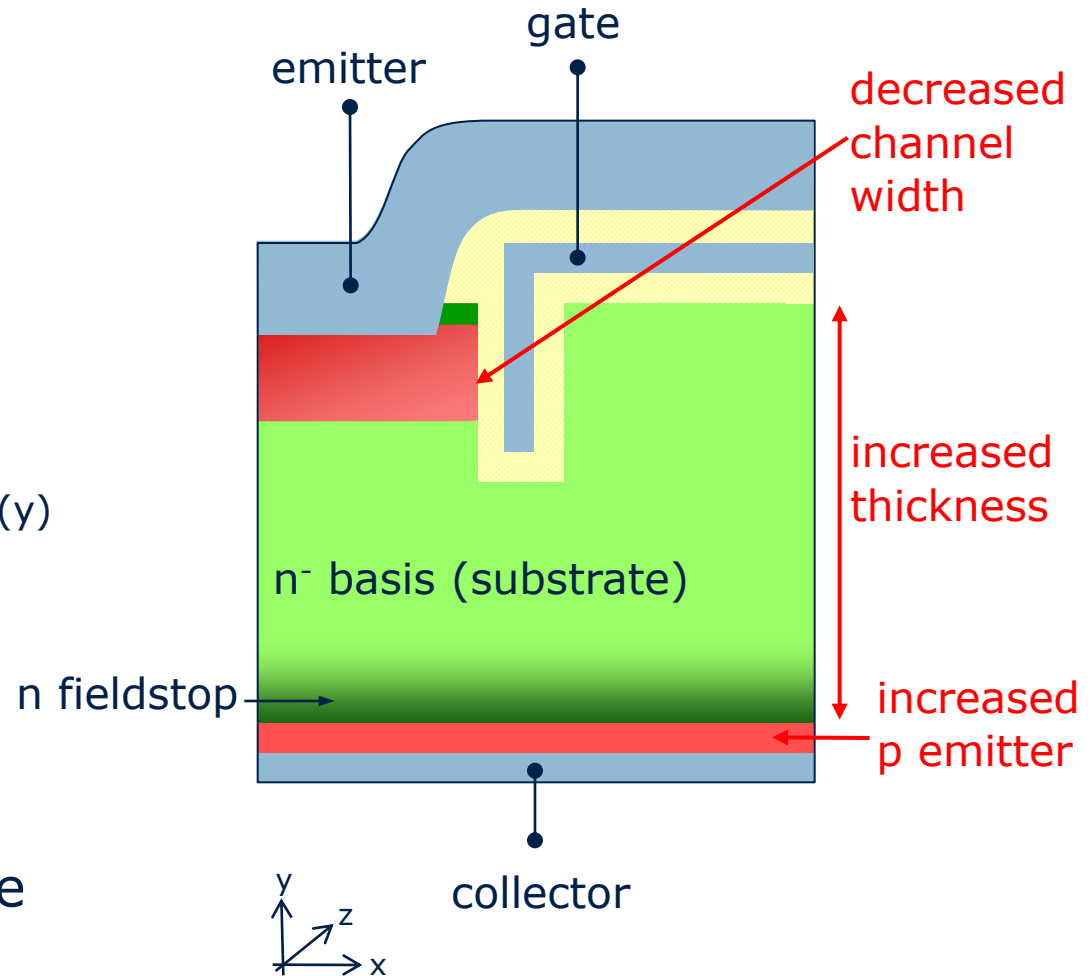
$$V_{\text{peak(max)}} = 277\text{V} + 15\% \cdot \sqrt{2} = 450\text{V}$$

Design and technology of the 650V IGBT4

- trench MOS-top-cell
- thin wafer technology
- field-stop concept

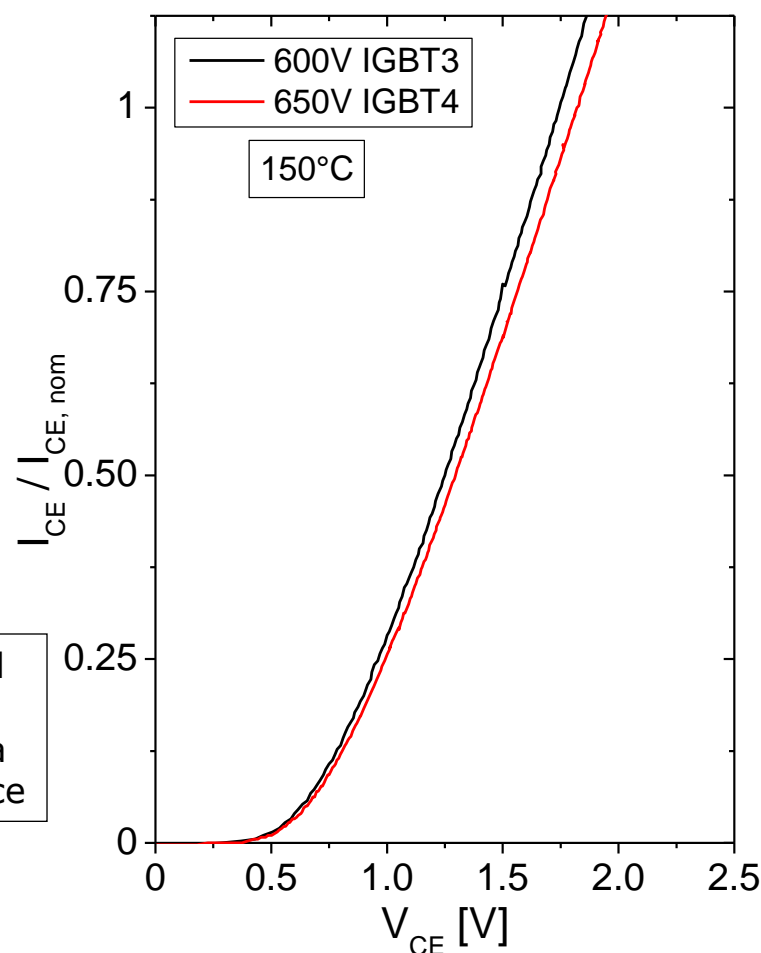
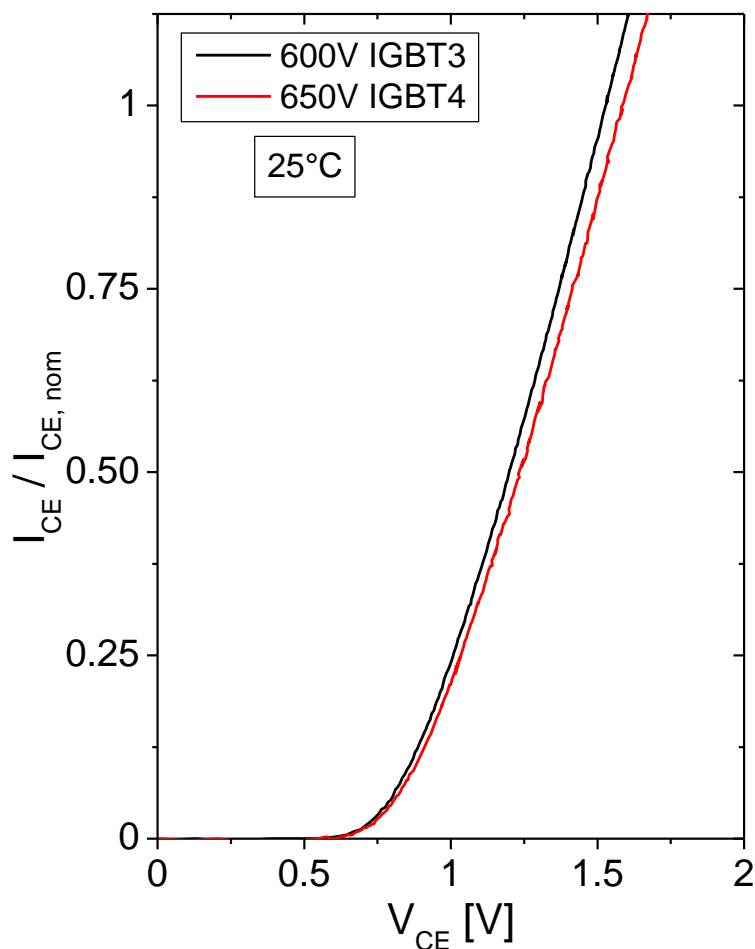
difference to 600V IGBT3:

- increased chip thickness (y)
~+15%
- reduced MOS channel width (z)
~-20%
- increased efficiency of the back side p-emitter



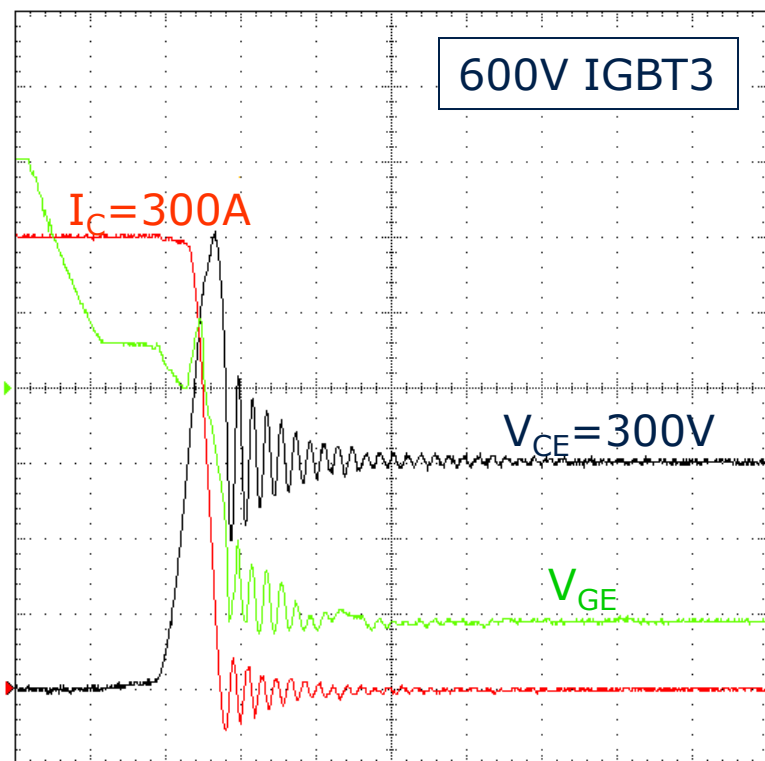
Static characteristics

- higher blocking voltage capability: 650V
- $V_{CE,sat}$ increase compared to 600V IGBT3:
~50mV at 150°C on module level

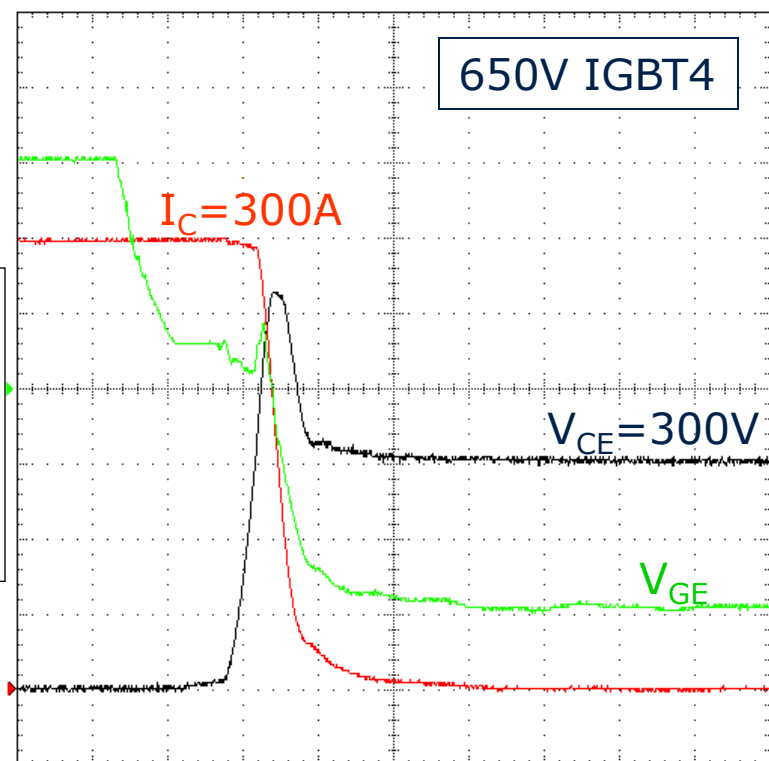


measured
on DBC
level for a
200A device

Dynamic characteristics



measured in
EconoDUAL™3
modules at
25°C
300V
300A
~60nH



t=0

1

2μs

t=0

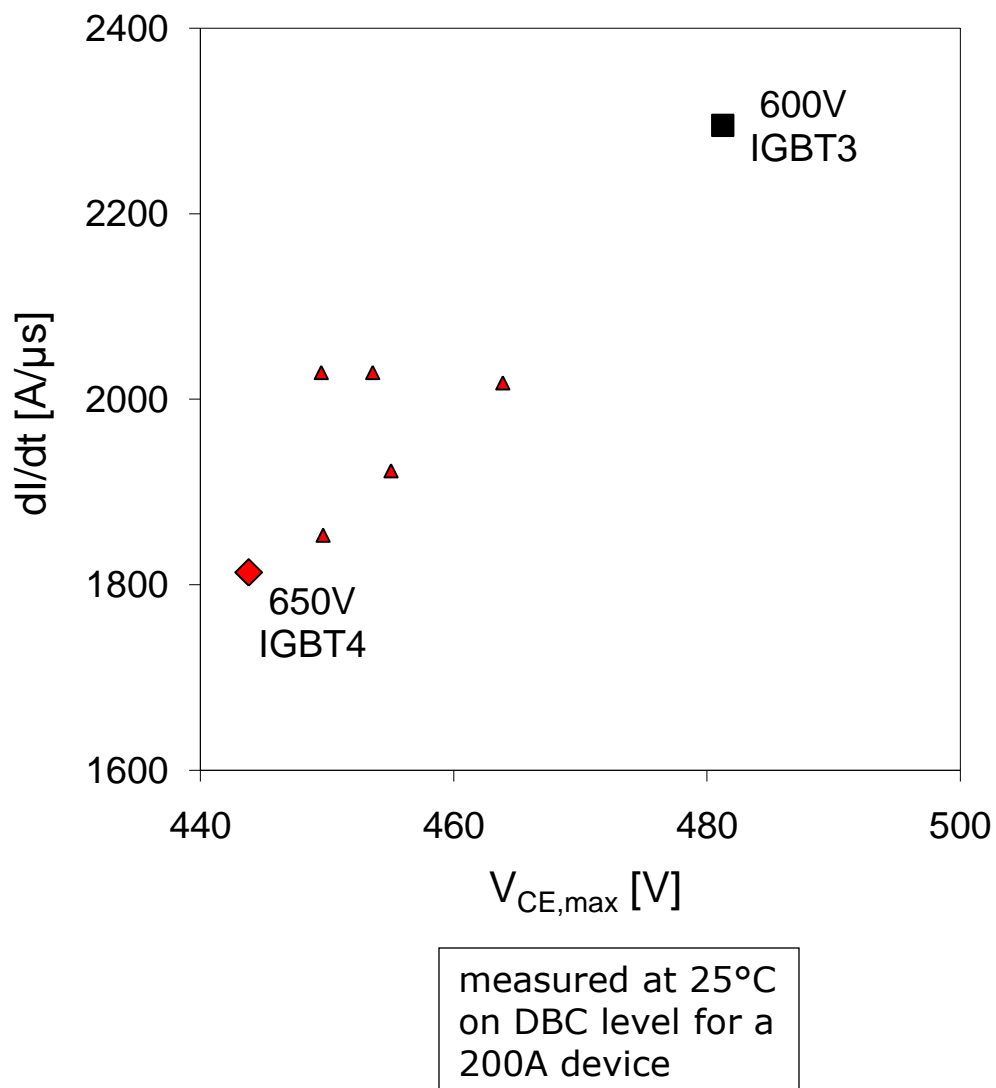
1

2μs

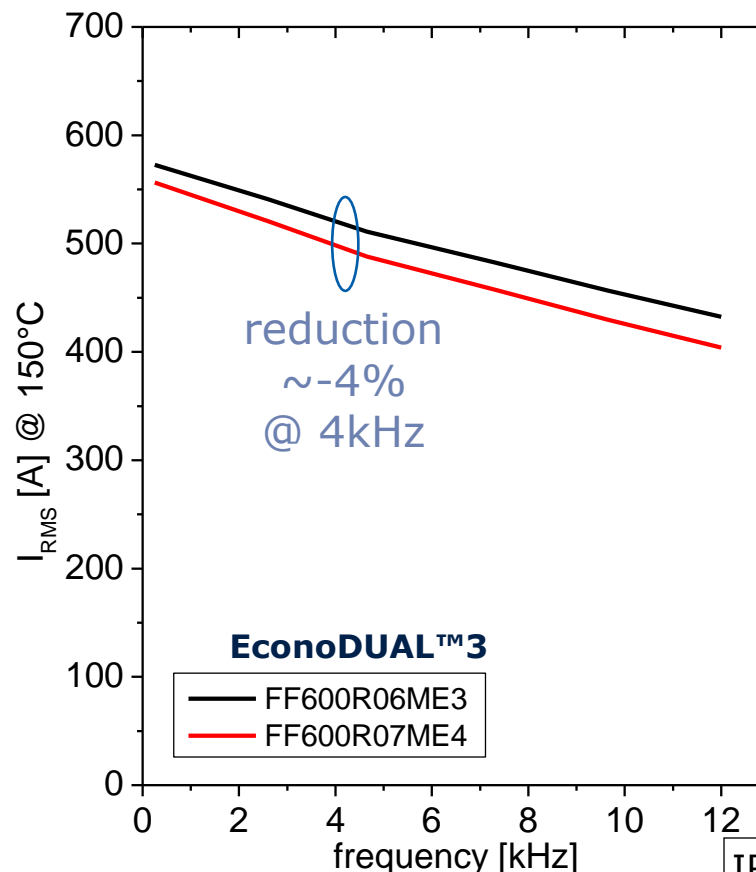
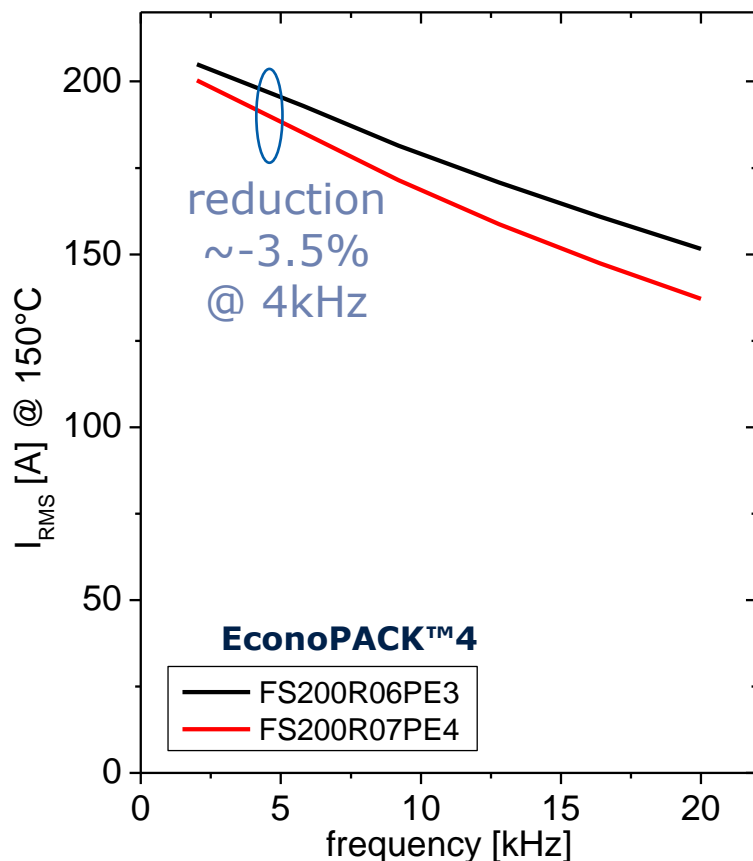
- softer switch-off behavior
- reduced turn-off current slope $dI/dt \rightarrow$ no oscillations at 25°C, less EMI efforts
- lower overshoot voltage
- still comparatively low on-state losses and turn-off losses

Softness: 600V IGBT3 vs. 650V IGBT4

- reduction of turn-off current slope dI/dt
(on module level by >20%)
- reduction of maximum overshoot voltage $V_{CE,max}$
(on module level up to 100V)



IPOSIM: RMS module current



■ reduction of the RMS module current:

~ -2 ... -10%
for frequencies
2 to 20kHz

~ -3 ... -7%
for frequencies
0.25 to 12kHz

IPOSIM sim.
conditions:
 $R_{th}(hs) = 0.09K/W$
 $T(ambient) = 35^{\circ}C$
 $T_{vj,op} = 150^{\circ}C$
 $\cos(\varphi) = 0.85$

Mechanism of thermal short-circuit destruction

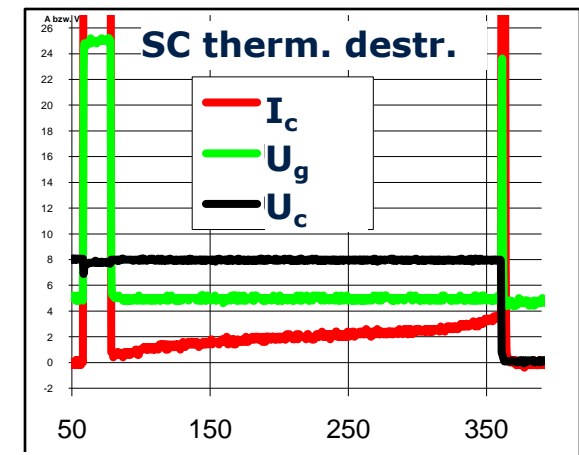
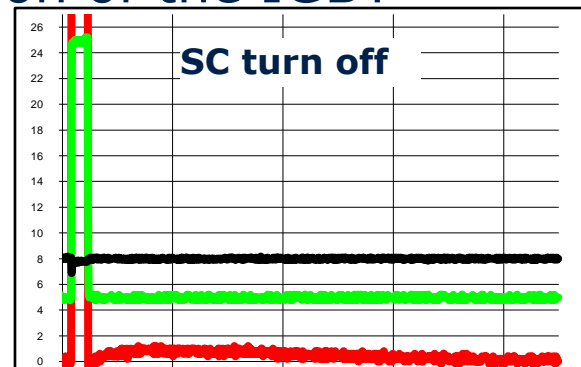
- heat generation in the chip center during the short circuit pulse
- temperature maximum at the end of the short-circuit pulse
- heat diffusion to the back side of the chip
 - temperature increase at the backside p-emitter → hole current
- heat diffusion to the front side of the chip
 - temperature increase at n-source → electron leakage current
 - pnp-amplification → hole current from the backside p-emitter
- hot leakage current → increasing chip temperature
- latch-up and destruction of the IGBT

→ F. Hille et al., ISPSD 2010:

„Failure mechanism and improvement potential of IGBT's short circuit operation“

■ 650V IGBT4:

- increased thermal budget (increased chip thickness)
- reduced short-circuit current (decreased MOS channel width)

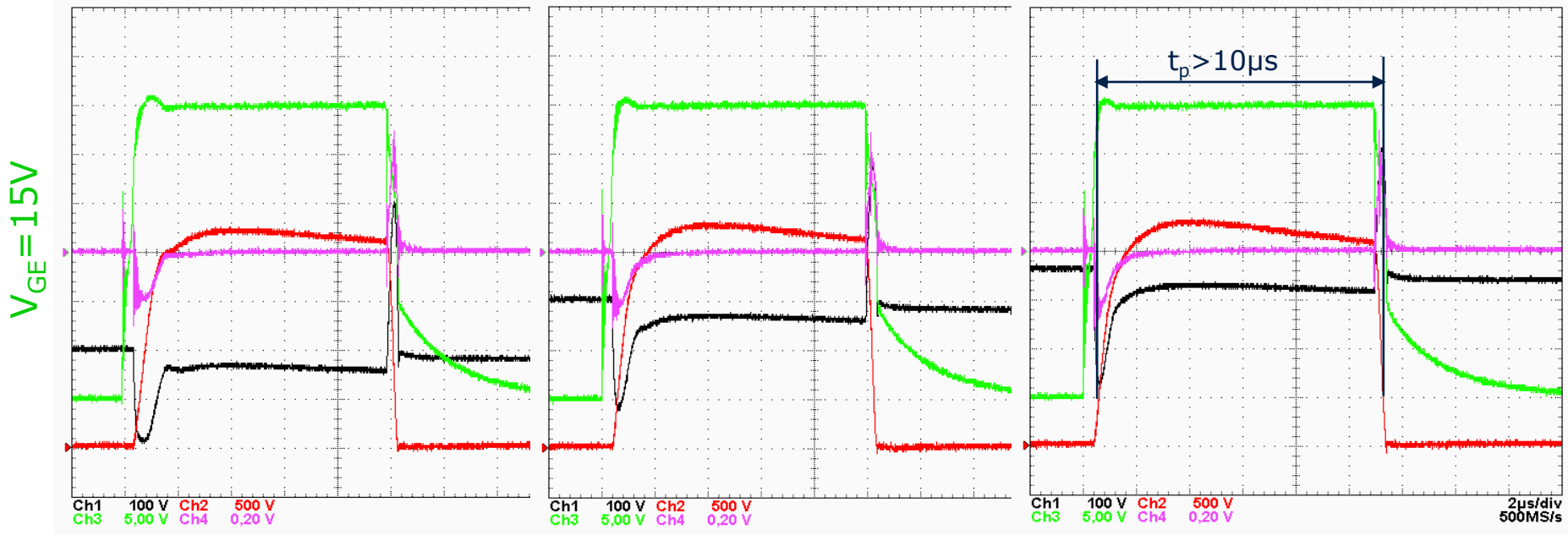


Short-circuit behavior

$V_{CE}=200V$

300V

360V



- short-circuit pulse withstand time $t_p > 10\mu s$
- short-circuit current about $4.5 I_{nom}$
- enhanced short-circuit withstand time
- different detection mechanisms possible

Power cycling capability

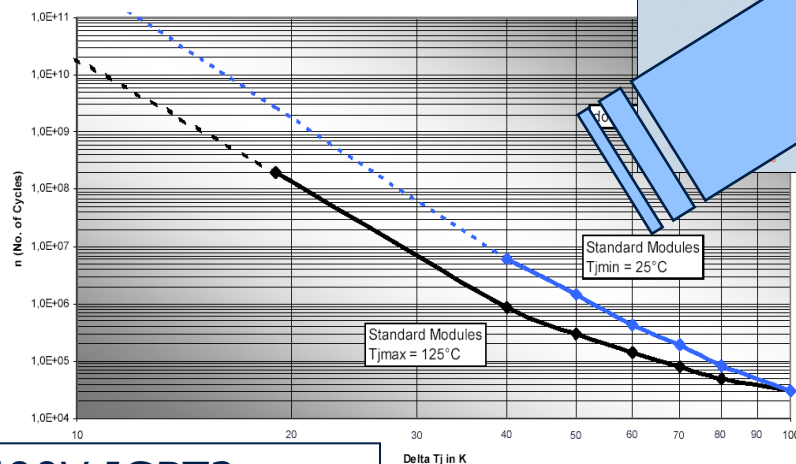
- high power cycling capability with the 650V IGBT4

- example:

$$T_{vj} = 25^{\circ}\text{C}, \Delta T = 40\text{K}$$

Reliability of IGBT-Modules

Power Cycling: Low-, Medium & High Power Standard Modules

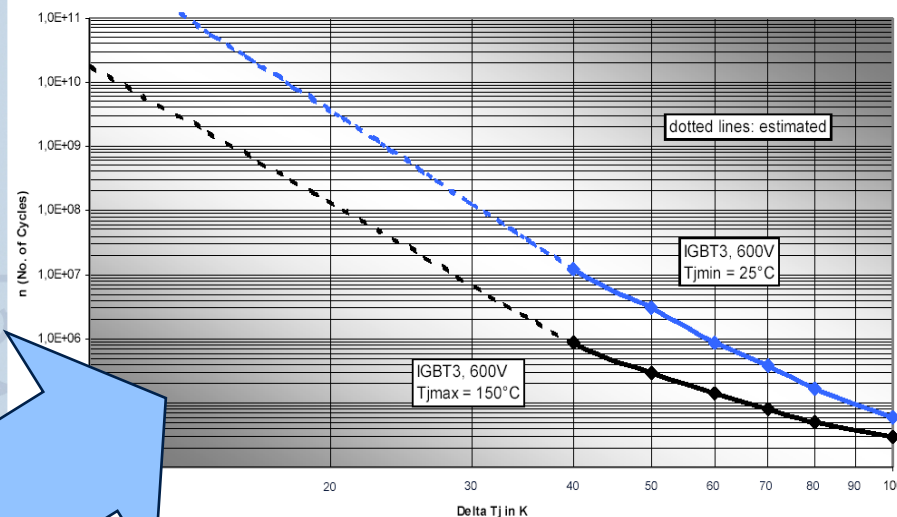


600V IGBT2:

~6 Mio cycles

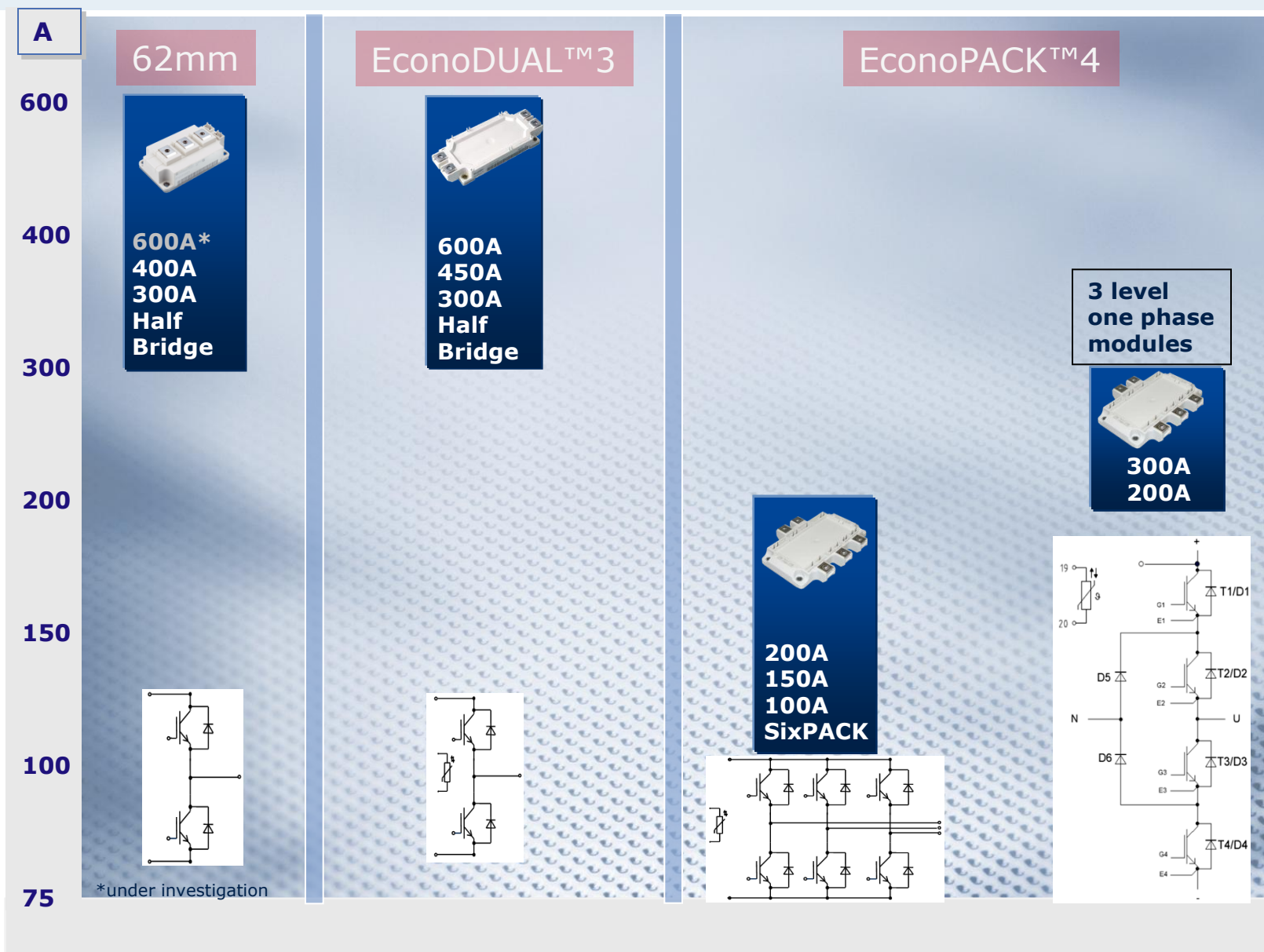
Reliability of IGBT-Modules

Power Cycling: IGBT3, 600V Standard Modules



600V IGBT3 / 650V IGBT4:
~15 Mio cycles

Medium Power target product portfolio 650V IGBT4



Conclusion

- 650V IGBT4:
 - increased chip thickness
 - reduced MOS channel width
 - increased efficiency of the back side p-emitter
- softer switch-off behavior:
 - lower overshoot voltage
 - reduced turn-off current slope dI/dt
 - reduced EMI efforts
- good trade-off: comparatively low on-state and turn-off losses
- enhanced short-circuit behavior: withstand time $>10\mu s$
- optimized device for larger current applications
- use of larger DC link voltages and/or higher inductances possible

A background image showing a person in a white lab coat and safety glasses, holding a clipboard, standing in a laboratory or industrial setting. The image is slightly blurred and has a light blue overlay.

We commit.
We innovate.
We partner.
We create value.



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